SURAGUS
Sensors & Instruments

Non-Contact Metrology Solutions for Solar Industry

S_PV_22

About Us

SURAGUS GmbH is a German metrology specialist developing and manufacturing non-contact material testing solutions for thin film materials. Our EddyCus® systems are installed at customer sites on six continents and are serviced and distributed through a worldwide network of sales and service partners. We serve numerous industries applying thin films in a wide variety of processes.

Technology

SURAGUS utilizes a unique high-frequency, wide range eddy current technology. This wide range, high frequency combination enables rapid testing of both very low and highly conductive materials. Our EddyCus® measurement systems (Eddy Current Solutions) excel with high sample rates and in non-contact setups, and come with several industrial interfaces and user-friendly software.

Portfolio

SURAGUS' portfolio comprises hand-held devices, table-sized benchtop testing solutions, robot based systems and standard & customized inline solutions. Standard and customized sensors are used to tailor to a large number of non-contact testing tasks including the measurement of physical parameters and defect detection.

Values

SURAGUS is a customer-focused and technology-driven company. A long-term and result-driven mutual cooperation between our customers and partners is of the highest importance to us. Our interdisciplinary R&D team transforms latest advancements in microelectronics and sensor manufacturing into novel testing solutions for our customers.

SURAGUS GmbH
Maria-Reiche-Straße 1
01109 Dresden
Germany

+49 351 32 111 520
info@suragus.com

www.suragus.com
www.sheet-resistance-testing.com

Engineered and Made in Germany

TÜV SÜD ISO 9001

jec GROUP WINNER OF 2016 INNOVATION AWARD

Process Monitoring

- Incoming Silicon wafer inspection
- Deposition (*PVD, CVD, etc.)*
- Etching / Polishing
- Doping
- Wet-processing

Measurements

- Sheet Resistance [Ohm/sq]
- Metal Layer Thickness [nm, µm]
- Resistivity [Ohm·cm]
- PN Junction Integrity Testing

Applications

- Wafer resistivity monitoring
- Sheet resistance monitoring of conductive layers (ITO at HJT)
- Metal thickness and sheet resistance of non-transparent (back) contacts (metals) Setups

Solutions

Single Point

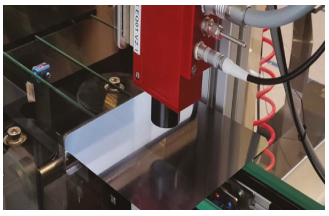
EddyCus® lab Series

Imaging

EddyCus® inline Series

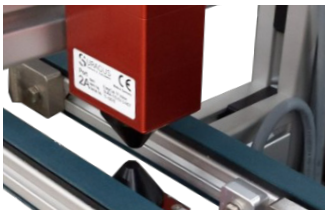
Inline

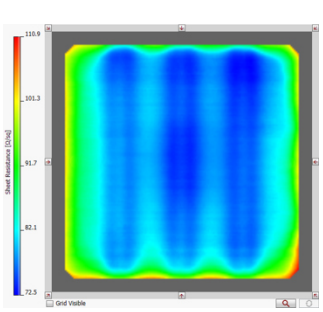
EddyCus® inline Series

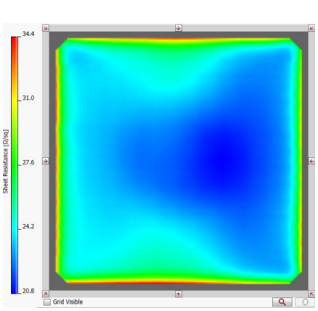


Inline

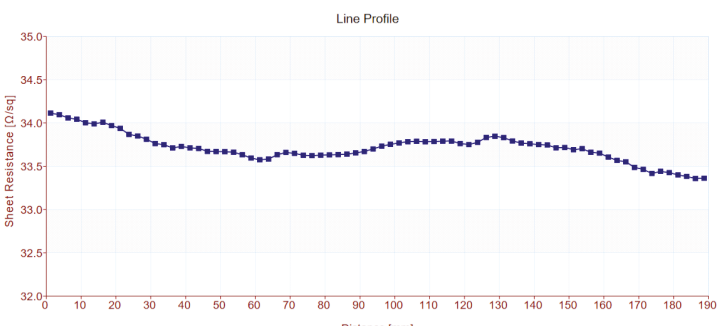
EddyCus® inline Series







P-doped Monocrystalline Silicon Wafer



Line Profile Analysis Exposes Homogeneity